

PROCESS CHANGE NOTICE **PRODUCT CHANGE NOTICE**

MAXIM INTEGRATED HEREBY ISSUES NOTIFICATION OF CHANGE
 THAT MAY AFFECT THE FOLLOWING CATEGORIES:

<input checked="" type="checkbox"/> DESIGN	<input type="checkbox"/> WAFER FAB	<input type="checkbox"/> ASSEMBLY	<input type="checkbox"/> TEST	<input checked="" type="checkbox"/> ELEC/MECH SPECS
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AFFECTED PRODUCT:

Ordering P/N: (See PN listing XLS in PCN ZIP file)

<p>CHANGE FROM: Die Revision: APX6</p> <p>Datasheet changes:</p> <ol style="list-style-type: none"> Offset error: +/-13 LSB Gain Error: +/-12 LSB Integral Nonlinearity: +/-2 LSB Positive Full-Scale Error: +/-16 LSB Negative Full-Scale Error: +/-16 LSB SNR: 89.5dB (min) SFDR: 96dB (min) THD: -96 dB (max) SCLK Period (CS Mode): 26ns (min) (VOVDD > 2.3V) SCLK Period (Daisy-Chain Mode): 36ns (min)(VOVDD > 2.3V) SCLK Low Time: 5 ns (min) SCLK High Time: 5 ns (min) CNVST Low to SDO D15 MSB Valid (CS Mode), VOVDD , 2.7V: 17ns (max) SCLK Valid Setup Time from CNVST Rising Edge: 5ns (min) SCLK Valid Hold Time from CNVST Rising Edge: 5ns (min) SDI Valid Setup Time from SCLK Falling Edge: 5ns (min) SDI High to SDO High, VOVDD > 4.5V, 15ns(max) SDI High to SDO High, VOVDD > 2.3V, 26ns(max) 	<p>CHANGE TO: Die Revision: AUC2</p> <p>Datasheet changes:</p> <ol style="list-style-type: none"> Offset error: +/-5.0 LSB (OVDD=\leq 3.6V) , +/-8.0 LSB (OVDD > 3.6V) Gain Error: +/-8 LSB Integral Nonlinearity: +/-1.5 LSB (OVDD =\leq 3.6V) , +/-2.25 LSB (OVDD > 3.6V) Positive Full-Scale Error: +/-5.5 LSB (OVDD =\leq 3.6V) , +/-7.5 LSB (OVDD > 3.6V) Negative Full-Scale Error: +/-7.5 LSB (OVDD =\leq 3.6V) , +/-9.0 LSB (OVDD > 3.6V) SNR: 89.7dB (min) SFDR: 99 dB (min) (OVDD =\leq 3.6V) , 96 dB (min) (OVDD > 3.6V) THD: -97.6 dB (max) (OVDD =\leq 3.6V) , -95.5 dB (max) (OVDD > 3.6V) SCLK Period (CS Mode): 25ns (min) (VOVDD > 2.3V) SCLK Period (Daisy-Chain Mode): 30ns (min)(VOVDD > 2.3V) SCLK Low Time: 6 ns (min) SCLK High Time: 6 ns (min) CNVST Low to SDO D15 MSB Valid (CS Mode), VOVDD , 2.7V: 18ns (max) SCLK Valid Setup Time from CNVST Rising Edge: 3ns (min) SCLK Valid Hold Time from CNVST Rising Edge: 3ns (min) SDI Valid Setup Time from SCLK Falling Edge: VOVDD > 4.5V, 3ns(min); VOVDD > 2.7V, 5ns(min); VOVDD > 2.3V, 6ns(min) SDI High to SDO High, VOVDD > 4.5V, 10ns(max) SDI High to SDO High, VOVDD > 2.3V, 20ns(max)
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JUSTIFICATION: Minor design modification to the reference buffer to enhance select static and dynamic performance specifications, improve settling time, and increase manufacturing throughput.

PCN # 1581

DATE: October 27, 2015

EXPECTED PCN SHIP DATE: April 9, 2018



Quality Assurance

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The datasheet is for the MAX11168 devices only.

Please see the attached datasheet for all changes and additional information to clarify the device operation.

TRACEABILITY: Maxim Integrated maintains full traceability by device marking, packaging labels and shipment documents.

Maxim Integrated's Change Notification System is designed to keep our customer base apprised of major product, manufacturing, or facility improvements.

Nasser Ali Chaouche

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Contact your local Maxim Integrated Company Representative

or

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